



第四章 基本单元电路

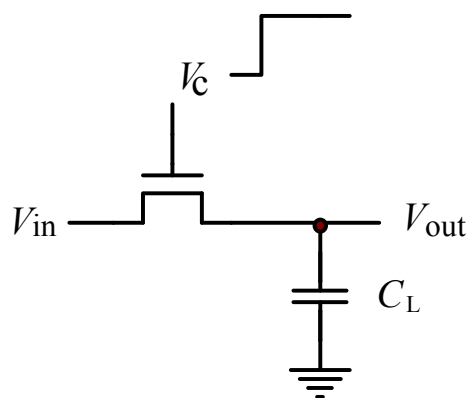
4.7 传输门基本特性



MOS传输门逻辑电路

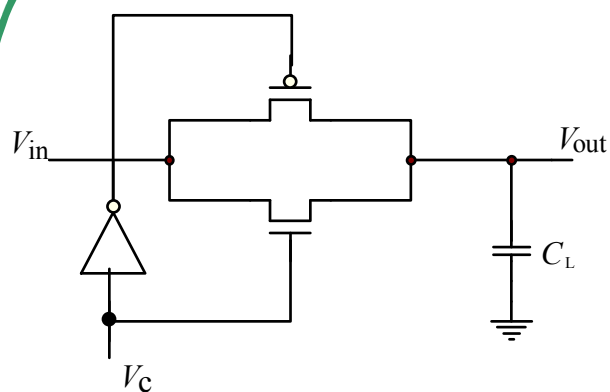
- **NMOS/PMOS**传输门特性
- **CMOS**传输门特性
- 传输门的级联
- **NMOS**传输门的电平恢复

MOS传输门结构

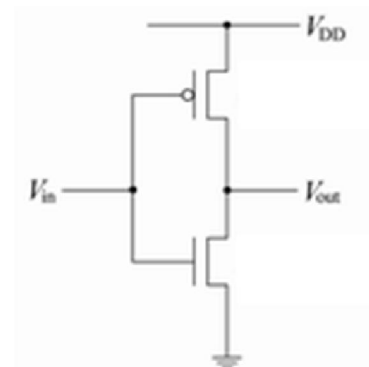


NMOS传输门
Pass Transistor

源、漏端不固定
双向导通



CMOS传输门
Transmission Gate
NMOS,PMOS并联
源、漏端不固定
栅极接相反信号
两管同时导通或
截止



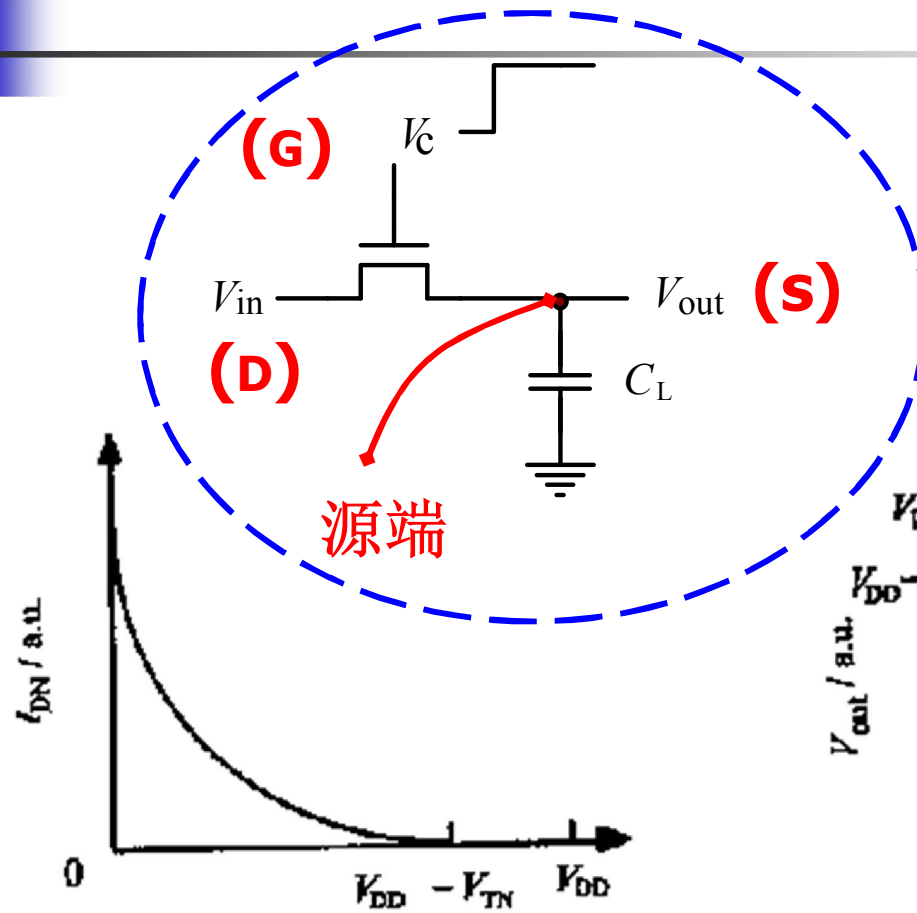
CMOS反相器

NMOS,PMOS串联
源端接固定电位、
漏端输出
栅极接相同信号
两管轮流导通或
截止

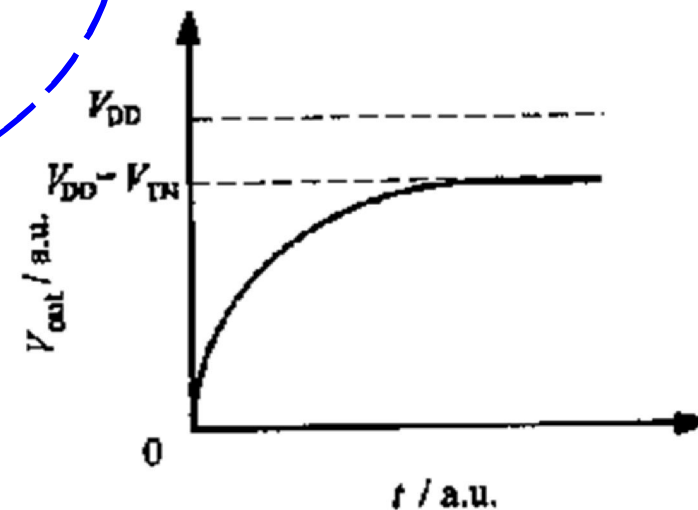
NMOS传输门传输高电平特性

$$V_{in}=V_{DD}, V_c=V_{DD}$$

Hints: $V_D=V_G$, 器件始终处于饱和区, 直到截止 (类似于饱和负载的特性)

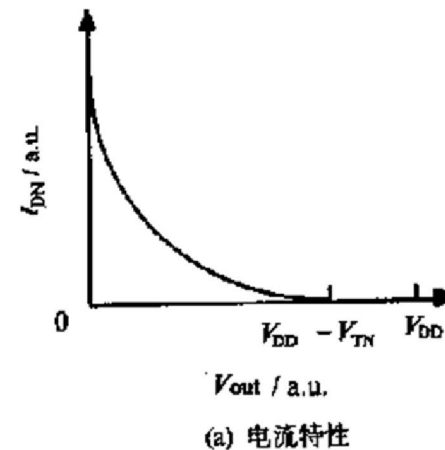
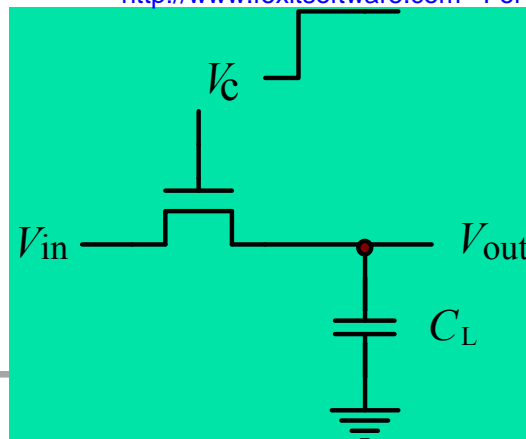
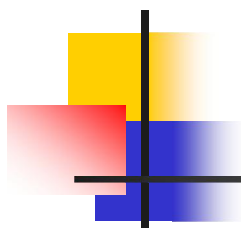


(a) 电流特性



(b) 输出电平的变化

NMOS传输高电平



- 输出电压：有阈值损失 $V_{in}=V_{DD}, V_c=V_{DD}, V_{out}=V_{DD}-V_{th}$

- 工作在饱和区，但是电流不恒定

- 衬偏效应
$$I_{DN} = K_N (V_{DD} - V_{TN} - V_{out})^2$$

- 增加阈值损失

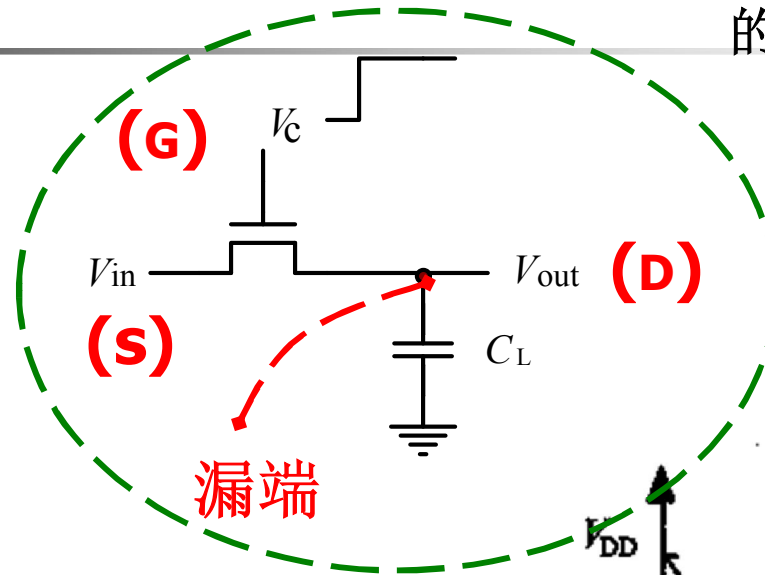
- 减小电流
$$V_{TN} = V_{TN0} + \gamma(\sqrt{2\phi_f + V_{out}} - \sqrt{2\phi_f})$$

- 低效传输高电平(电平质量差，充电电流小)

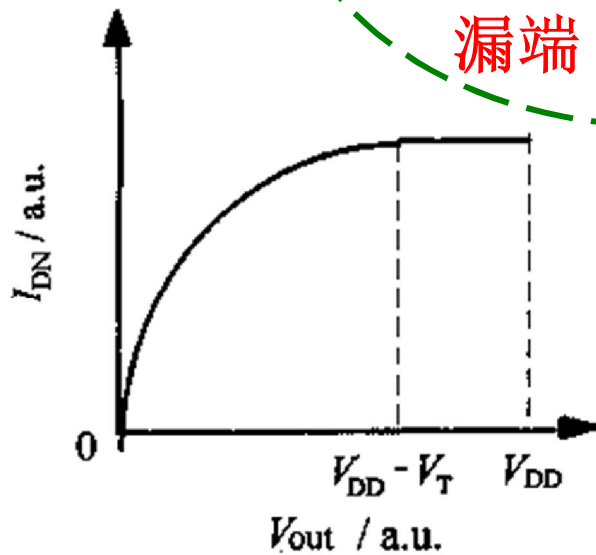
NMOS传输门传输低电平特性

Hints:器件先处于饱和区
后处于线性区

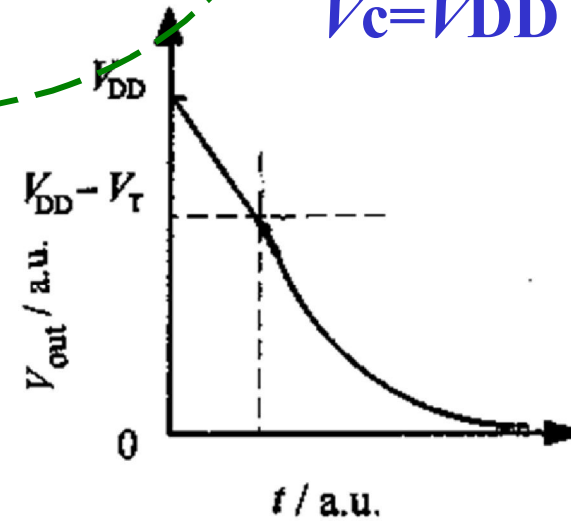
(类似于**CMOS**反相器中的
的**NMOS**管)



$V_{in}=0,$
 $V_c=V_{DD}$

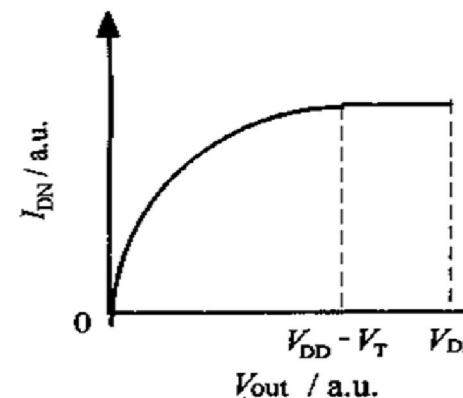
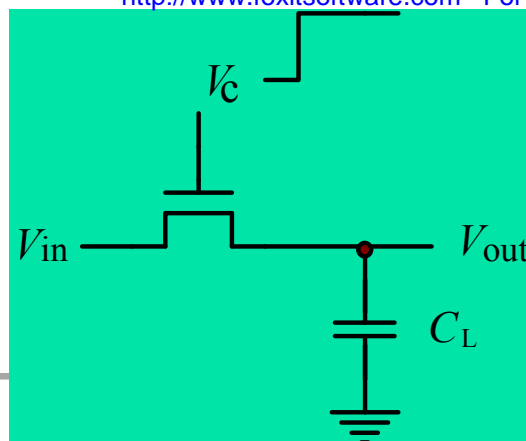
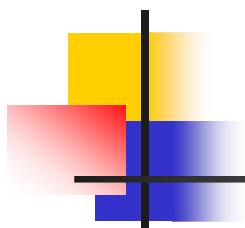


(a) 电流特性



(b) 输出电平的变化

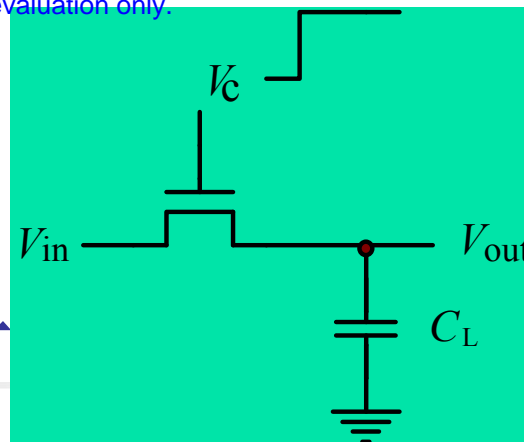
NMOS传输低电平



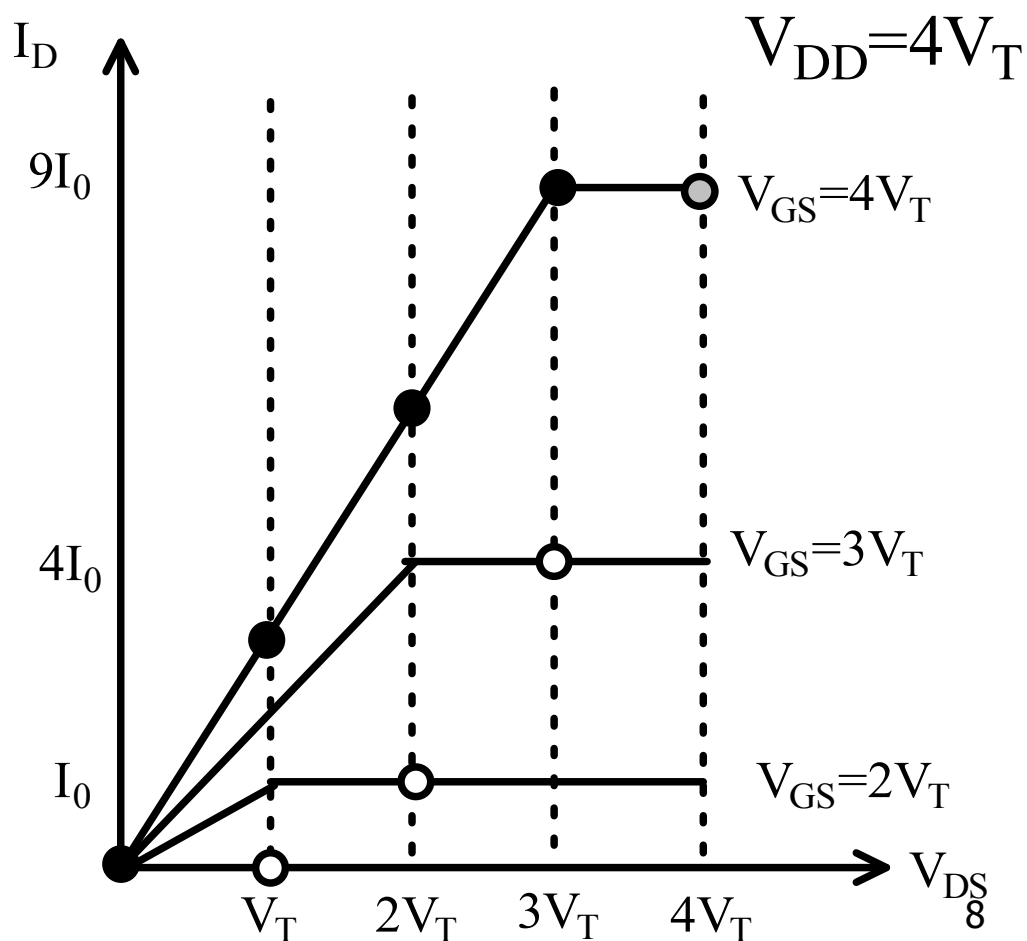
(a) 电流特性

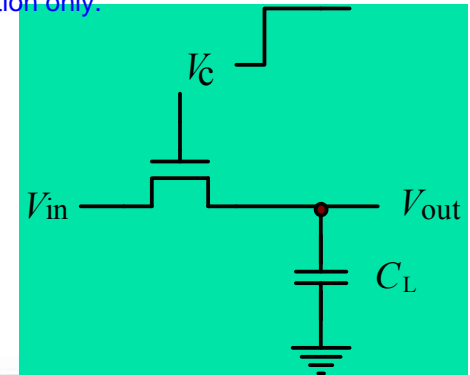
- 输出电压：没有阈值损失 $V_{in}=0, V_c=V_{DD}, V_{out}=0$
- 先工作在饱和区，后进入线形区
- 没有衬偏效应 $I_{DN1} = K_N (V_{DD} - V_{TN})^2$
- 高效传输低电平 $I_{DN2} = 2K_N (V_{DD} - V_{TN})V_{out}$
(电平质量好，充电电流大)

NMOS传输门等效电阻

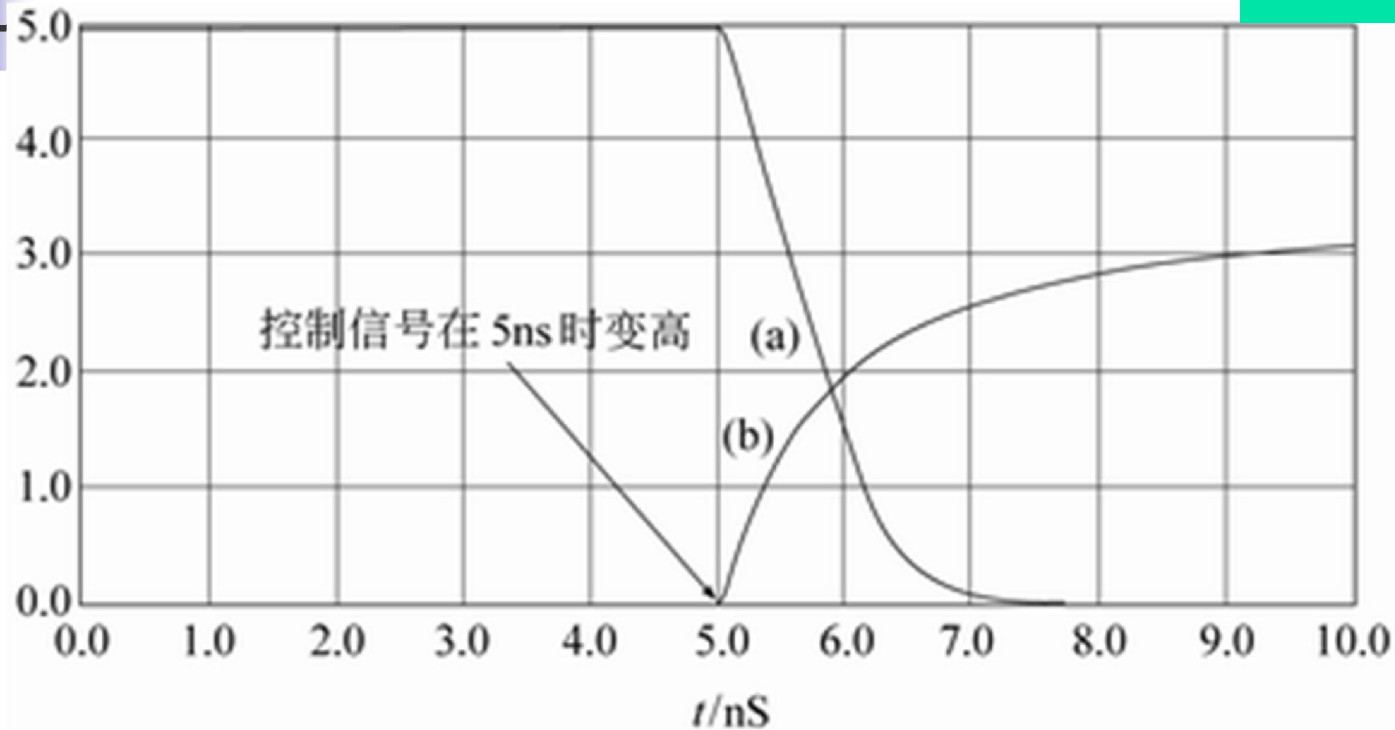


- 估算**NMOS**传输门等效电阻
- 传输低电平（深颜色点），传输高电平（浅颜色点）
- 分别求出平均电阻
- 传输高电平等效电阻约为低电平**2—3**倍



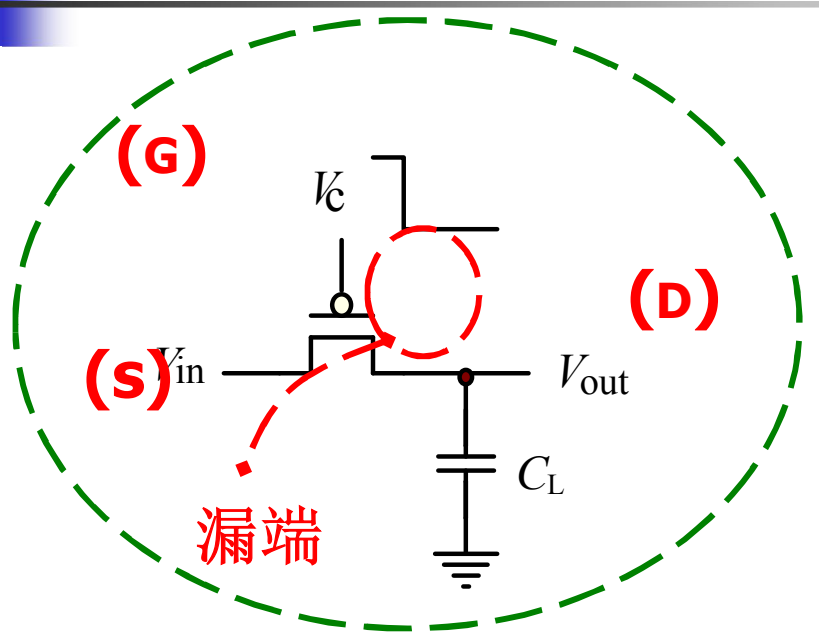


NMOS传输高电平和低电平



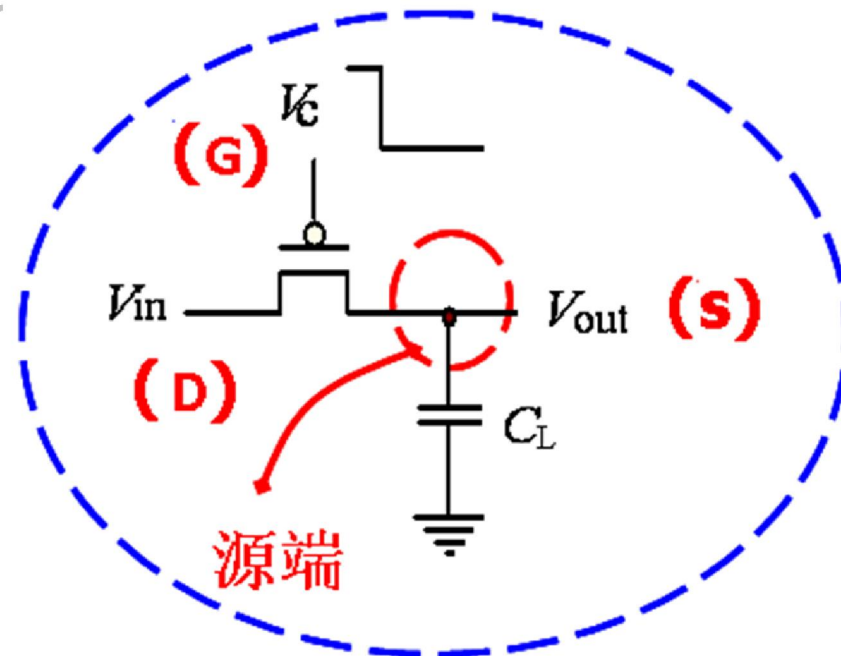
- 由于工作状态不同，以及衬偏效应的影响
- NMOS传输高电平过程的等效电阻近似为传输低电平时的2-3倍

PMOS传输门传输特性



传输高电平情况

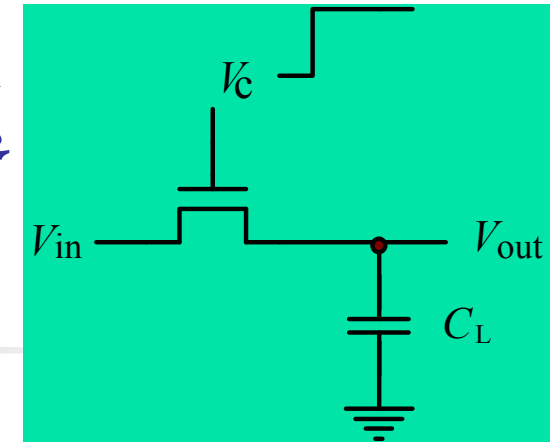
器件先处于饱和区，
后处于线性区



传输低电平情况

器件始终处于饱和区，
直到截止

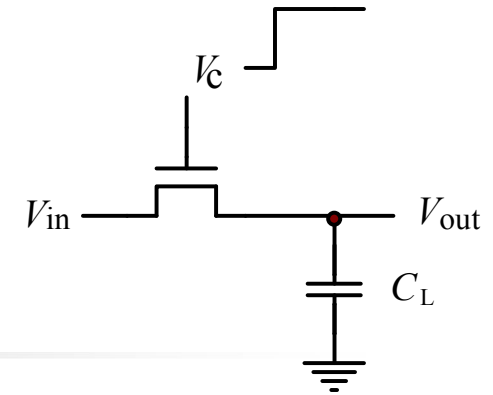
NMOS/PMOS传输门: RC延迟



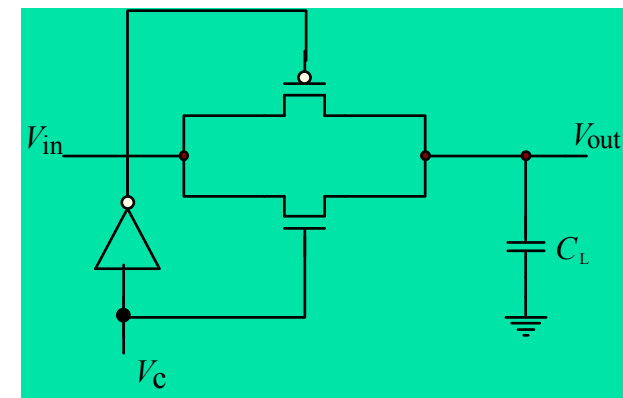
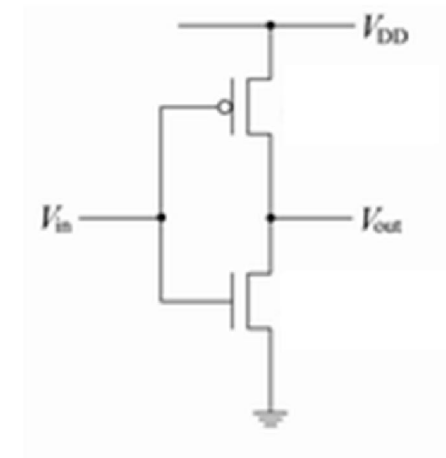
- 沿用反相器部分的分析模型，宽度为**W**的**PMOS**导电因子为**K0**，等效电阻为**R0**，漏电容为**C0**，并有迁移率**2**倍近似
- 如果负载电容只有传输管的漏电容，则宽度为**W/2**的**NMOS**的传输延迟：
- 多级串联的传输门可以根据集总或者**elmore**模型计算

$$t_{pHL} \propto \frac{1}{4} R_0 C_0$$
$$t_{pLH} \propto \frac{1}{2} R_0 C_0$$

传输管 (NMOS/PMOS传输门)



- 结构简单
- 有阈值损失
- **NMOS**高效传输低电平，低效传输高电平
- **PMOS**载流子迁移率小，**NMOS**传输门应用更多

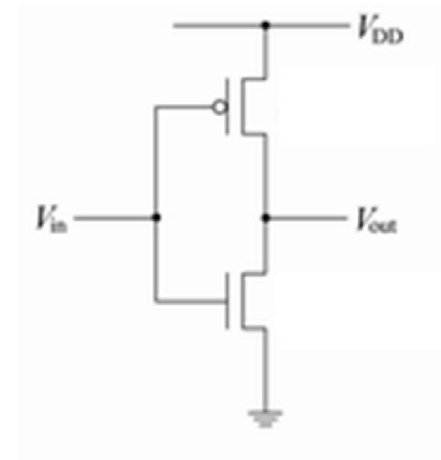
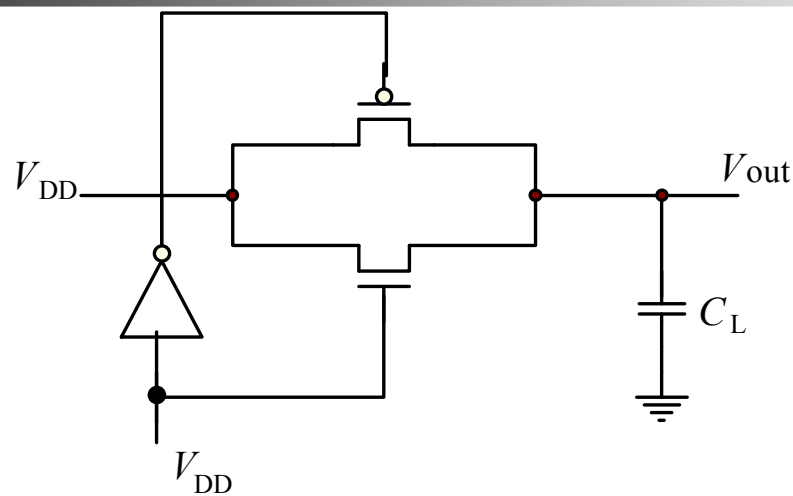
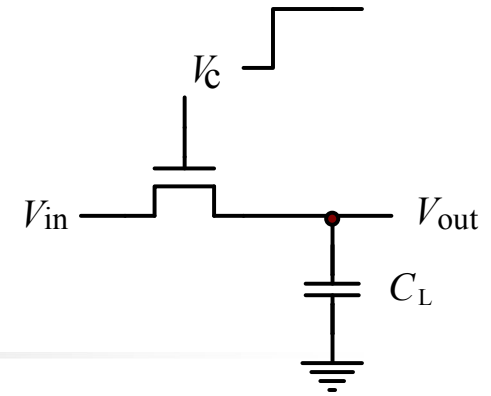




MOS传输门逻辑电路

- **NMOS/PMOS**传输门特性
- **CMOS**传输门特性
- 传输门的级联
- **NMOS**传输门的电平恢复

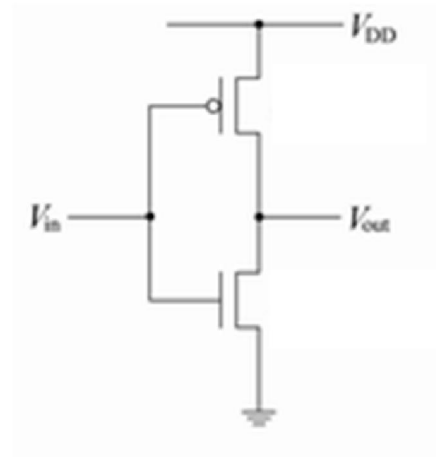
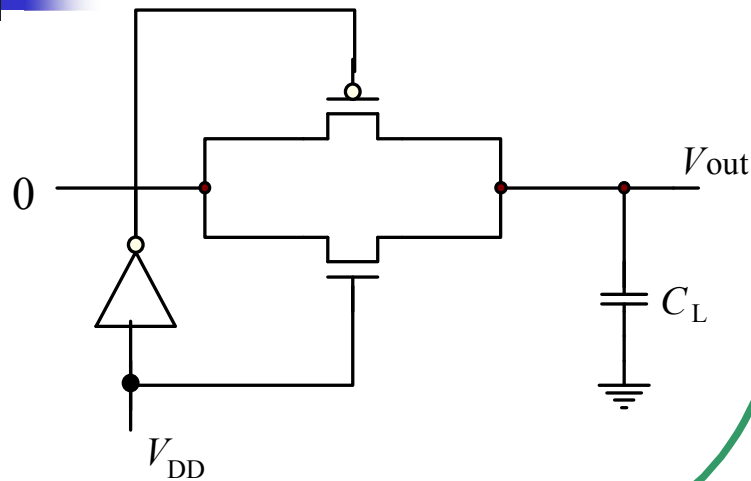
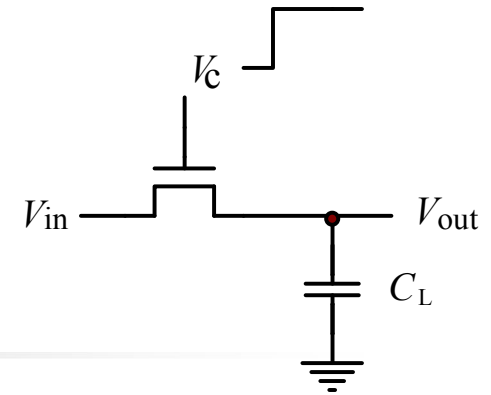
CMOS传输门传输高电平特性



传输高电平分为**3**个阶段:

- (1) $V_{out} \leq -V_{TP}$, **NMOS和PMOS都饱和**;
- (2) $-V_{TP} < V_{out} < V_{DD} - V_{TN}$, **NMOS饱和,PMOS线性**;
- (3) $V_{out} \geq V_{DD} - V_{TN}$, **NMOS截止,PMOS线性**。

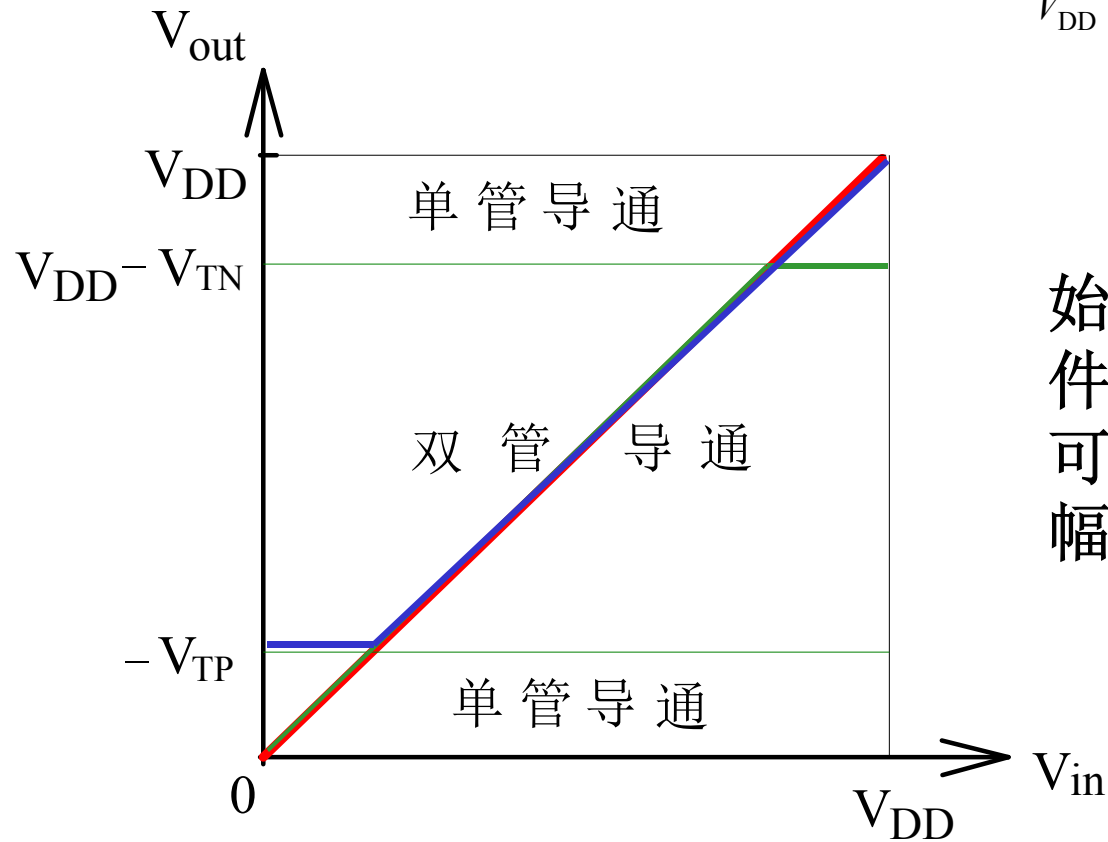
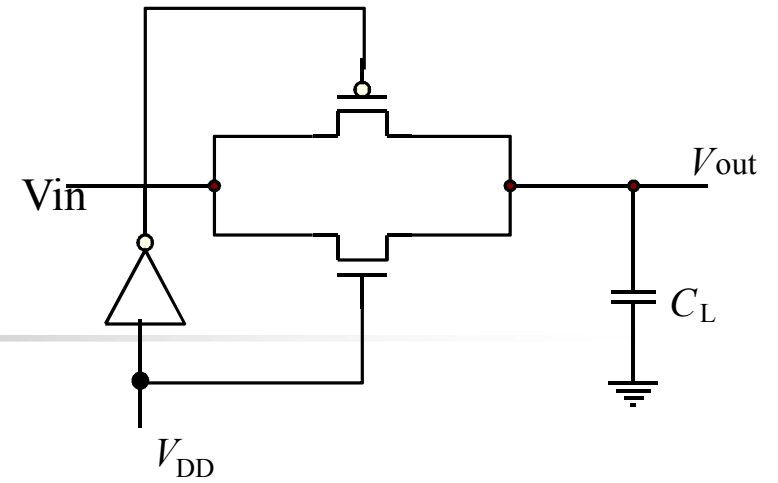
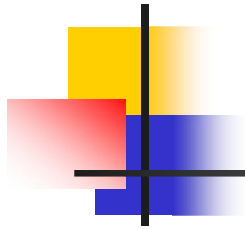
CMOS传输门传输低电平特性



传输低电平分为**3**个阶段：

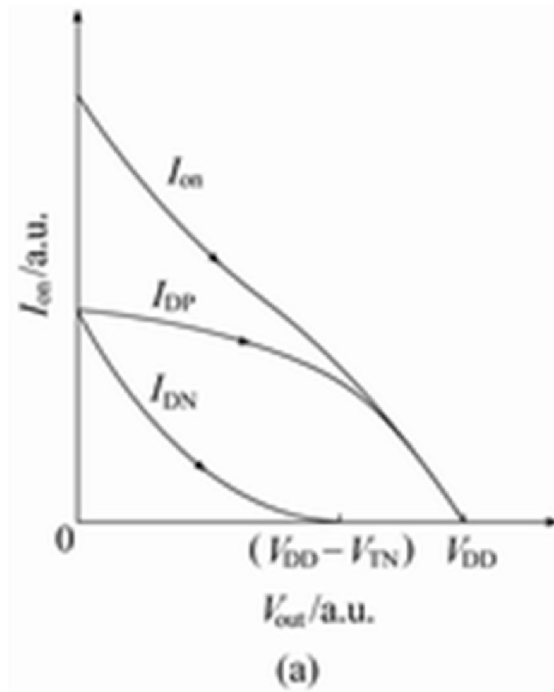
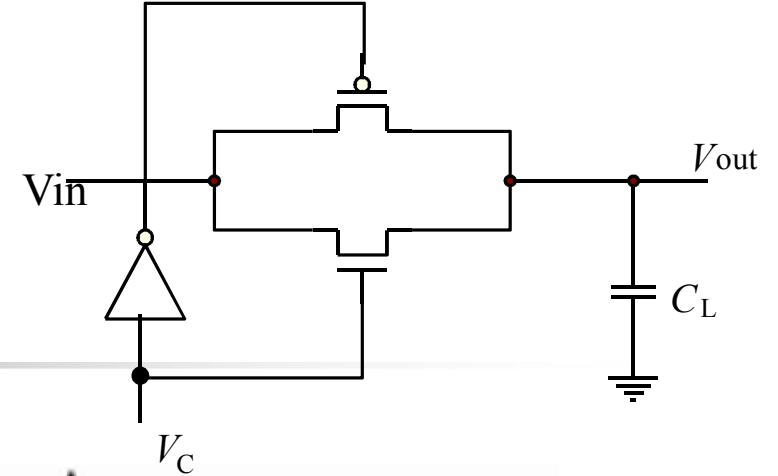
- (1) $V_{out} \geq V_{DD} - V_{TN}$ ，**NMOS**和**PMOS**都饱和；
- (2) $V_{DD} - V_{TN} > V_{out} > -V_{TP}$ ，**NMOS**线性，**PMOS**饱和；
- (3) $V_{out} \leq -V_{TP}$ ，**NMOS**线性，**PMOS**截止。

CMOS传输门直流电压传输特性

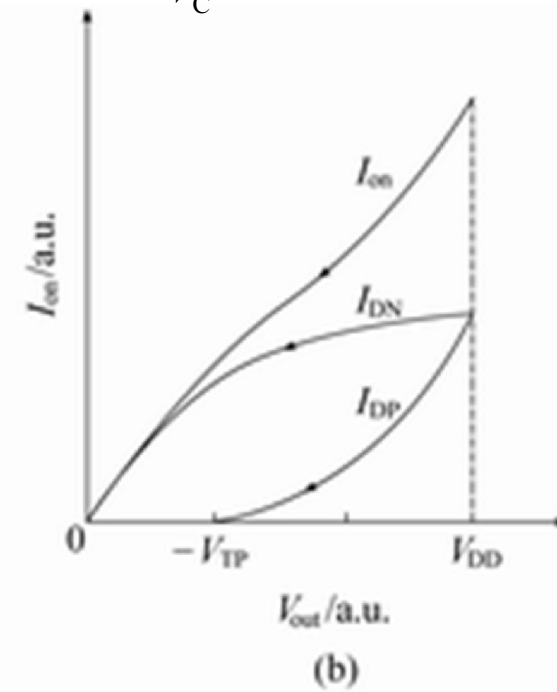


始终有一个器件是导通的，
可以传输全摆幅的信号

CMOS传输门导通电流的变化

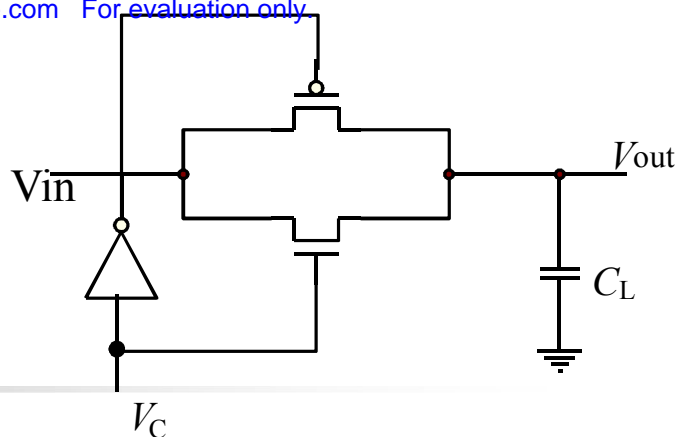


传输高电平

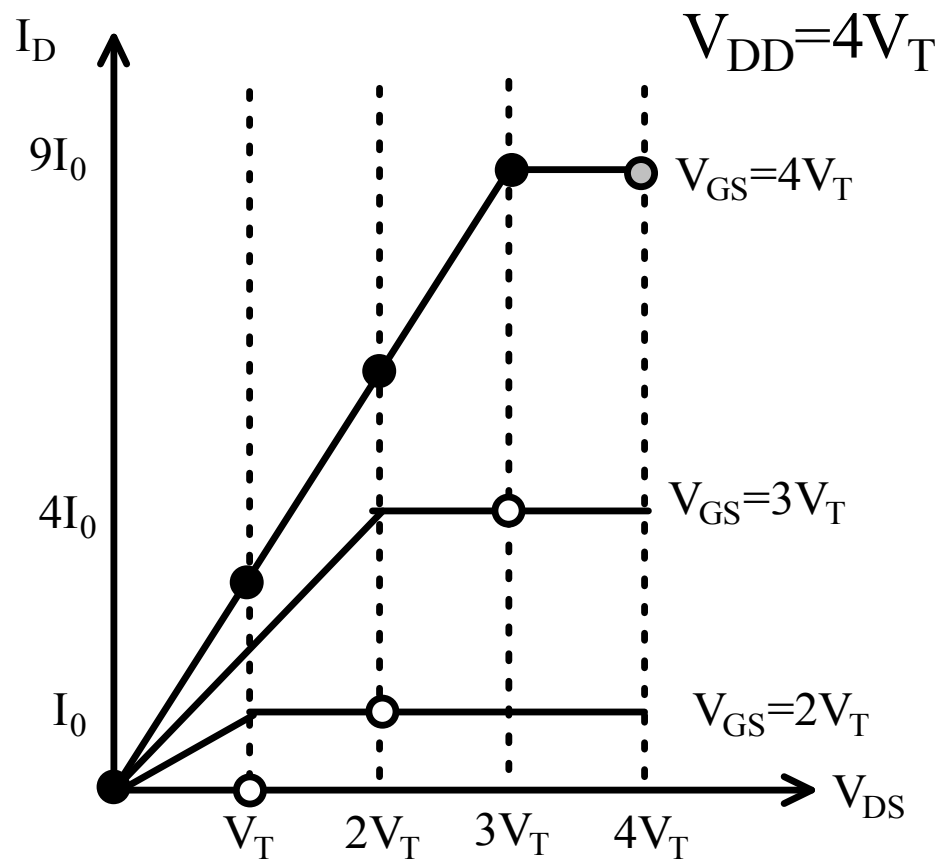


传输低电平

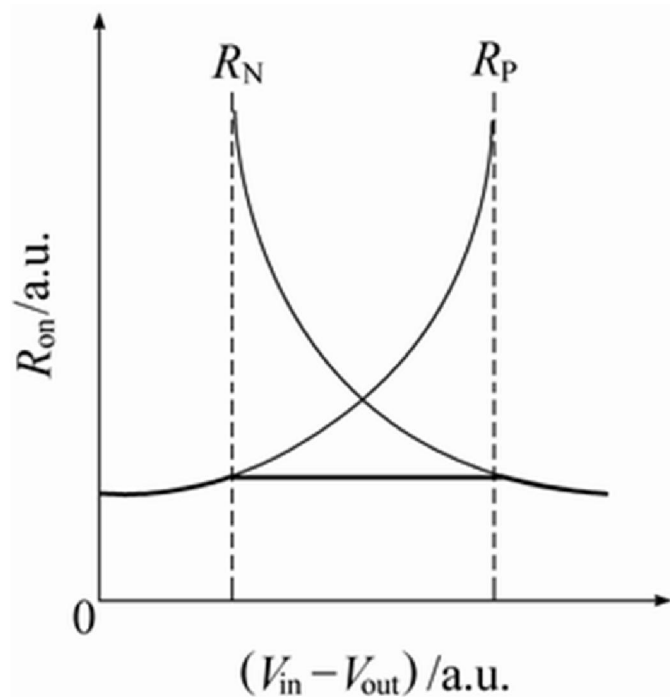
CMOS传输门导通电流



- 假设**CMOS**传输门的器件阈值电压和导电因子均相等，并忽略衬偏
- 高效传输（深颜色点），低效传输（浅颜色点）
- 二者之和为**CMOS**传输门导通电流
- 电流随**Vds**近似线性变化



CMOS传输门导通电阻的变化



传输延迟时间

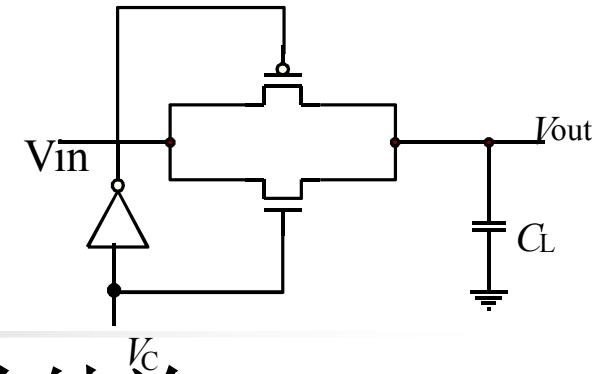
$$t_p = R_{on} C_L$$

传输低电平

$$R_{on} = \left(\frac{1}{R_N} + \frac{1}{R_P} \right)^{-1}$$

对称设计时 $R_{on} = \frac{1}{2K(V_{DD} - 2V_T)}$

CMOS传输门：RC延迟



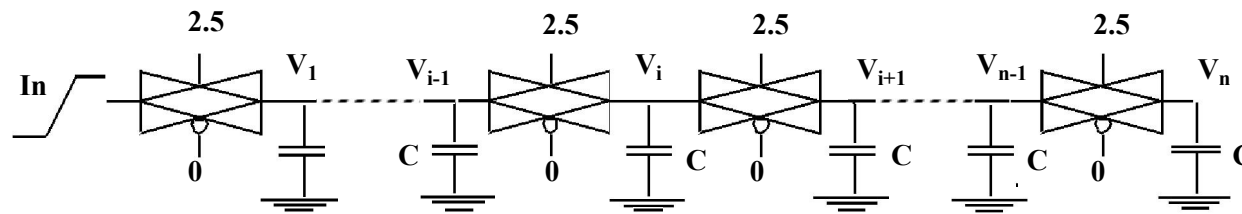
- 利用高效电阻为低效电阻一半的结论
- 对称设计： $K_n = K_p = 2K_0$ ， $W_p = 2W_n = 2W$ ， $R_n = R_p = R_0/2$
- 如果负载电容只有传输管的漏电容，则传输延迟： $t_{pHL} = t_{pLH} \propto R_0 C_0$
- 相同尺寸： $W_p = W_n = W$ ， $K_n = 2K_p = 2K$ ， $R_n = R_p/2 = R_0/2$ ，则传输延迟： $t_{pLH} \propto R_0 C_0$ $t_{pHL} \propto 0.8 R_0 C_0$
- CMOS传输门NP器件宽度相同为最优



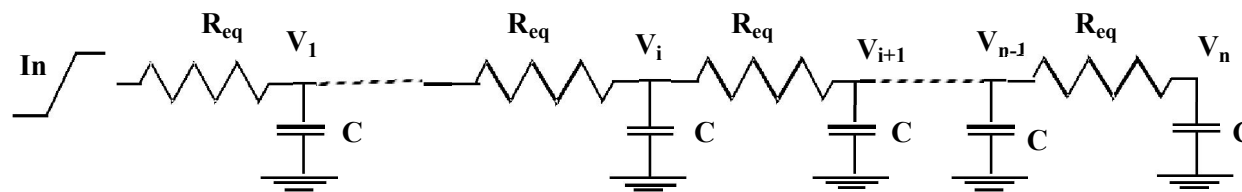
MOS传输门逻辑电路

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- **NMOS**传输门的电平恢复

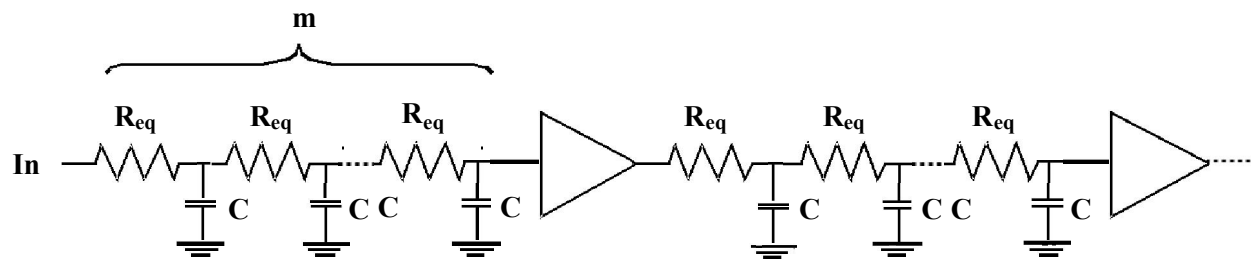
传输门的级联：RC网络



(a)

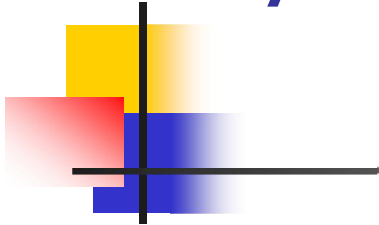


(b)



(c)

Delay Optimization



- Delay of RC chain

$$t_p = 0.69 \sum_{k=0}^n CR_{eq}^k = 0.69 CR_{eq} \frac{n(n+1)}{2}$$

平方增加

- Delay of Buffered Chain

$$t_p = 0.69 \left[\frac{n}{m} CR_{eq} \frac{m(m+1)}{2} \right] + \left(\frac{n}{m} - 1 \right) t_{buf}$$

线性增加

$$= 0.69 \left[CR_{eq} \frac{n(m+1)}{2} \right] + \left(\frac{n}{m} - 1 \right) t_{buf}$$

$$m_{opt} = 1.7 \sqrt{\frac{t_{pbuf}}{CR_{eq}}}$$

传输门级联最多**3-4**个，再多则需要插入缓冲器

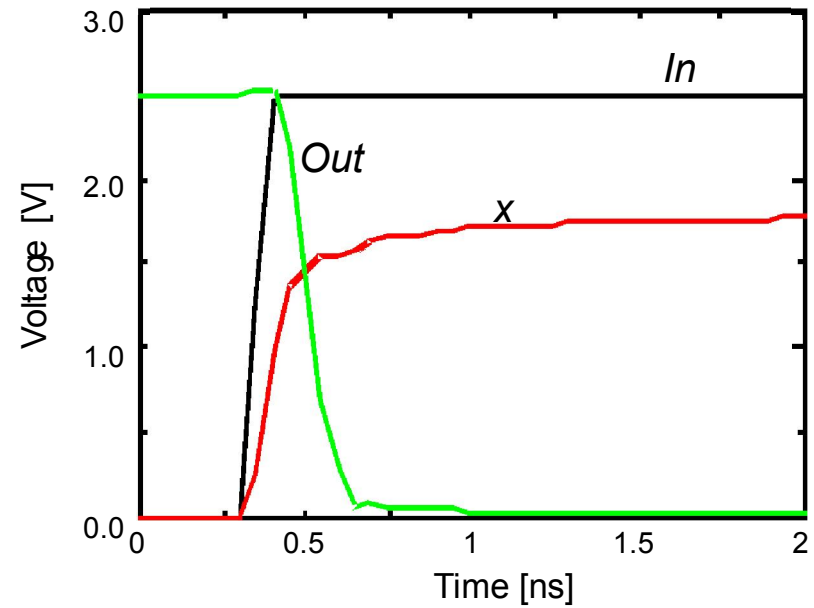


MOS传输门逻辑电路

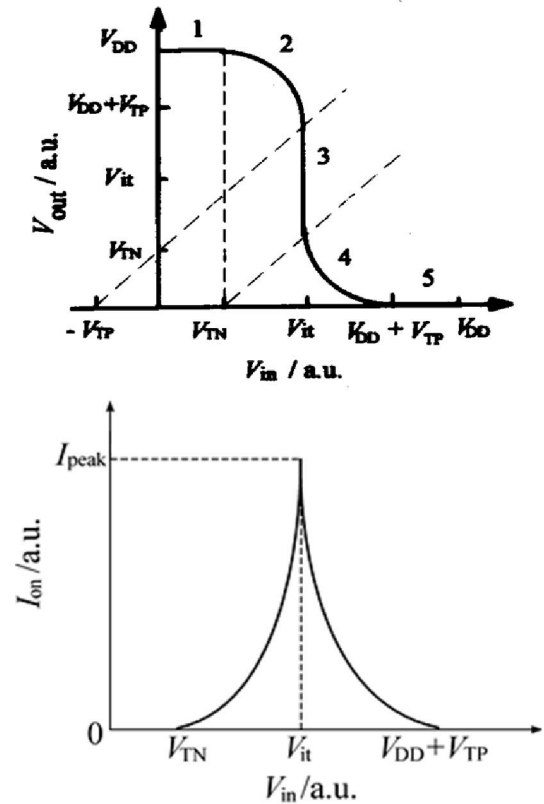
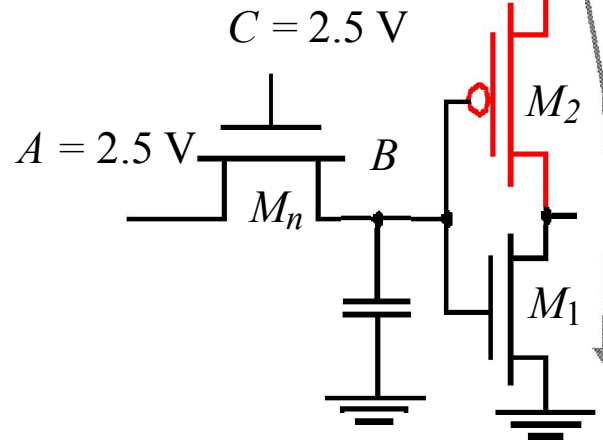
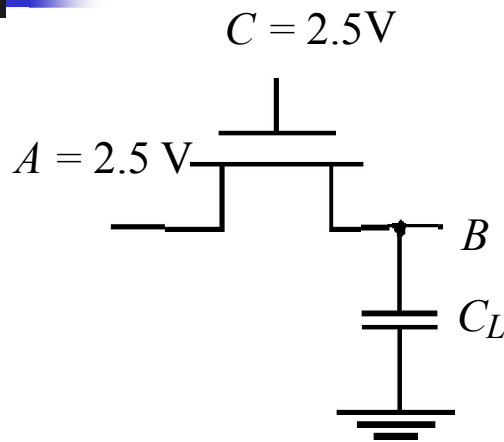
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NMOS传输高电平：阈值损失

V_{DD} In Out
 $0.5\mu\text{m}/0.25\mu\text{m}$ x $1.5\mu\text{m}/0.25\mu\text{m}$
 $0.5\mu\text{m}/0.25\mu\text{m}$ $0.5\mu\text{m}/0.25\mu\text{m}$



NMOS传输门



V_B does not pull up to 2.5V, but $2.5V - V_{TN}$

- 阈值损失降低了噪声容限，并引起静态短路功耗
- 可以采用CMOS传输门，但是结构复杂

NMOS 传输门: 电平恢复器件

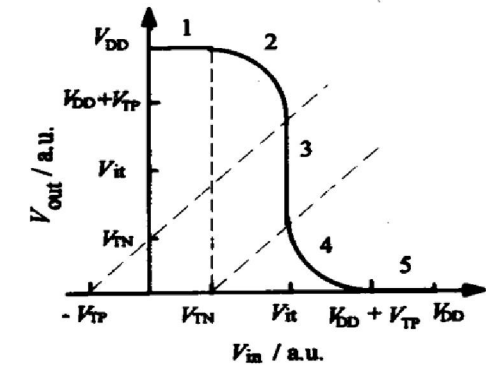
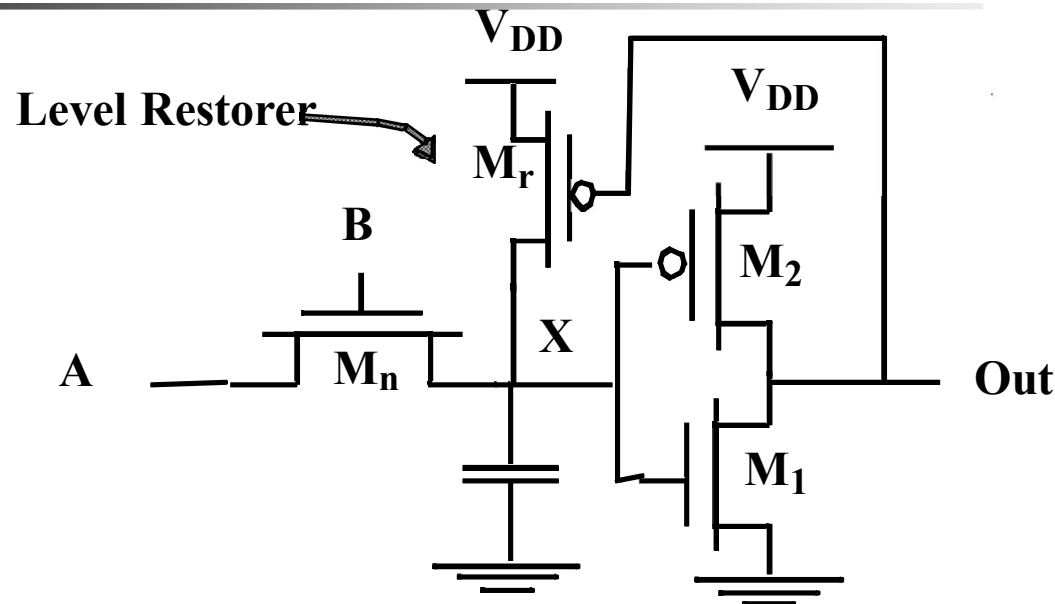
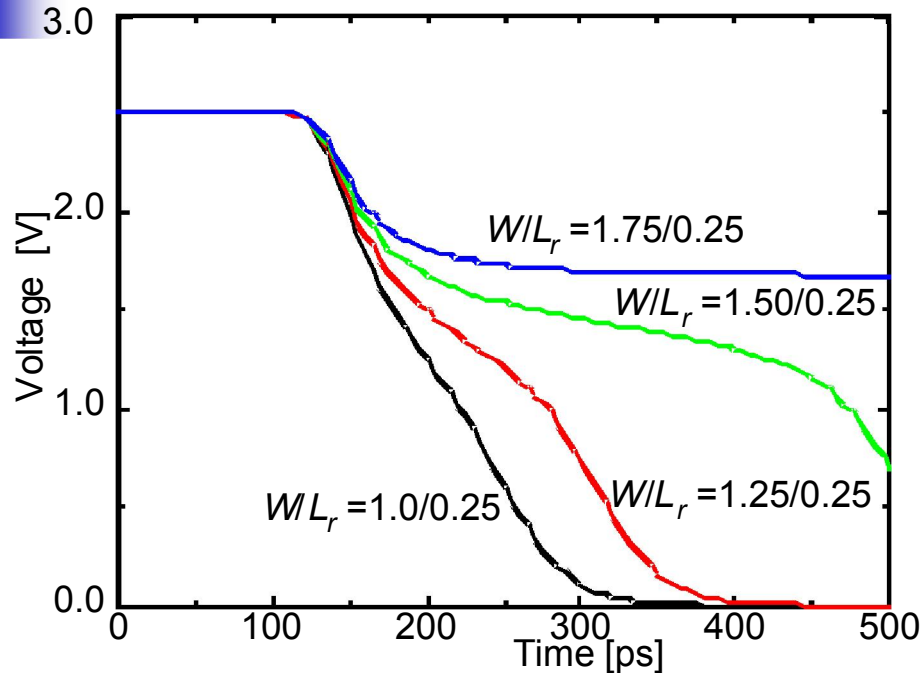
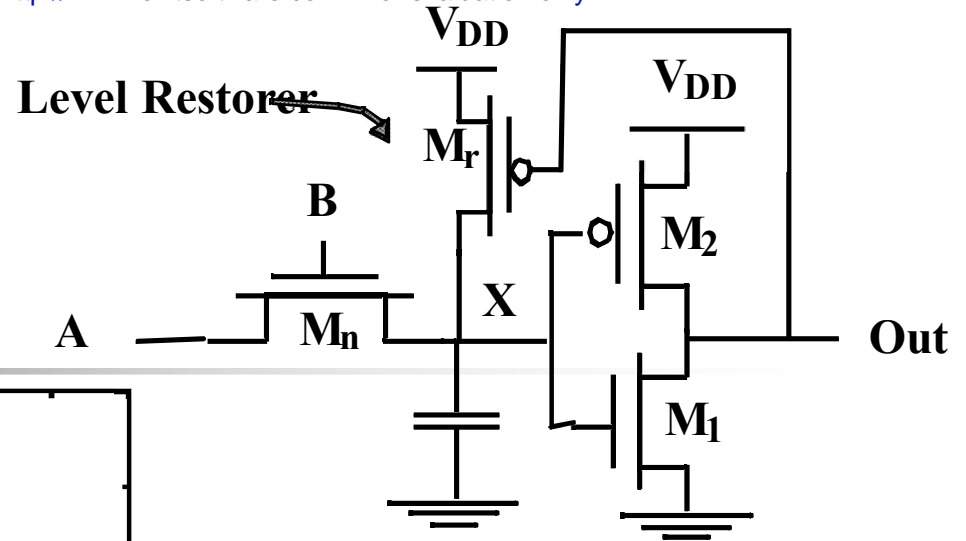


图 4.1.4 理想 CMOS 反相器的直流电压传输特性曲线



- 优点：输出信号全摆幅
- 缺点：增加了X和out节点电容，X节点放电过程Mr和Mn竞争
- 折中方案：限制Mr电流

Restorer Sizing



- 电平恢复作用的PMOS器件Mr的宽长比不能太大，否则电路无法工作
- Mr一般取最小尺寸L×L，这样引入漏区电容最小
- 如果前级NMOS传输门串联级数较多，Mr甚至可以取为倒比例 (W/L<1)